

The Technical Association of Refractories, Japan

Certified Reference Material Series for X-ray Fluorescence Analysis of Refractories

J R R M 7 0 1 (Alumina-Zirconia-Silica Refractory)
Results of Analyses

Constituent	SiO ₂	Al ₂ O ₃	Fe ₂ O ₃	TiO ₂	CaO	MgO	Na ₂ O	K ₂ O	Cr ₂ O ₃	ZrO ₂ (+HfO ₂)	HfO ₂	ZrO ₂ ^{*3}	Unit : mass%		
													Uncertified value		
Certified value	28.47	10.10	2.010	4.965	2.075	0.477	1.847	0.024	1.011	48.96	0.850	48.11	0.007	0.027	
Laboratories	L ₁	28.28 p	10.16 e	2.018 i	4.968 i	2.094 i	0.456 i	1.868 a	0.031 a	1.009 i	48.60 m	0.830 x	—	0.008 i	0.022 e
	L ₂	28.44 p	10.10 e	2.034 c	4.944 i	2.054 i	0.475 i	1.842 f	0.026 f	0.989 i	48.84 m	0.837 i	—	0.008 i	0.037 c
	L ₃	28.42 h	10.30	1.980 c	4.986 c	2.084 a	0.476 a	1.842 a	0.021 a	0.992 a	49.26 m	0.827 x	—	—	—
	L ₄	28.30 p	10.02 e	2.025 i	4.964 i	2.135 i	0.505 i	1.858 a	0.026 a	1.007 i	49.15 m	0.855 i	—	0.009 i	—
	L ₅	28.60 h	10.09 e	1.999 c	4.953 c	2.009 a	0.483 a	1.838 a	0.019 a	1.052 a	48.93 m	0.853 x	—	0.004 a	0.022 e
	L ₆	28.53 h	10.00 e	2.028 c	4.986 i	2.091 i	0.487 i	1.862 a	0.024 a	1.011 i	48.72 m	0.870 i	—	0.006 i	0.030 e
	L ₇	28.67 p	10.09 e	1.984 c	4.941 x	2.041 a	0.446 a	1.809 a	0.020 a	1.039 a	49.00 g	0.865 i	—	—	—
	L ₈	28.50 p	10.04 v	2.008 c	4.979 e	2.094 a	0.486 a	1.860 a	0.022 a	0.988 a	49.15 m	0.866 x	—	0.007 e	0.022 e
Average	(\bar{x})	28.468	10.100	2.0095	4.9651	2.0753	0.4768	1.8474	0.0236	1.0109	48.956	0.8504	48.106	0.0070	0.0266
Standard deviation (Reproducibility without laboratories) $s_{x_{(T)}}^{*1}$	0.130	0.096	0.0206	0.0192	0.0392	0.0184	0.0196	0.0039	0.0236	0.210	0.0170	—	0.0017	0.0068	
Uncertainty C (95%) ^{*2}	0.11	0.08	0.017	0.016	0.033	0.015	0.016	0.003	0.020	0.18	0.014	0.18 ^{*4}	0.002	0.008	

(Note) * 1 $s_{I(T)}$ is intermediate precision without a time condition.* 2 The half-width confidence interval C (95%) = $t_{\ell=1.05} \times s_x / \sqrt{\ell}$ (ℓ = number of laboratories)* 3 $ZrO_2 = ZrO_2(+HfO_2) - HfO_2$ * 4 $s_{x_{ZrO_2}} = \sqrt{(s_{x_{ZrO_2(HfO_2)}})^2 + (s_{x_{HfO_2}})^2}$

(1) List of laboratories : Krosaki Corporation, Kawasaki Refractories Co.,Ltd., Yotai Refractories Co.,Ltd., Asahi Glass Co.,Ltd., Harima Ceramic Co.,Ltd., Shinagawa Refractories Co.,Ltd., Toshiba Ceramics Co.,Ltd., Toshiba Monofrax Co.,Ltd.

(2) Analytical techniques : JIS R 2013(Method for chemical analysis of refractory containing alumina, zirconia and silica) a;AAS, c;colorimetry,e;Ionexchange-chelatometry, f:flammetry, g:Cupfronn Gravimetry, h:dehydratmetry+colorimetry, i:ICP-AES, m:Mandelic acid Gravimetry, p:coagulatmetry +colorimetry,v:Cupfronn Separation-chelatometry, x:XRF

(3) Analytical values : Each value is the average of two values obtained by two measurements on different days. These analysis values are shown converted into LOI (Loss on ignition) component free values from the February 22, 2008 v20080222 version on.

(4) Outlier tests were carried out by Grubbs test. The samples rejected by Grubbs tests were discussed in view of analytical techniques and it was determined whether the outliers should be adopted or not.

(5) Date of preparation : June, 1996

Prepared, and Values given and certified by

The Technical Association of Refractories, Japan

New Ginza Bldg., 3-13, Ginza 7-chome, Chuo-ku, Tokyo 104-0061, Japan

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The Technical Association of Refractories, Japan

Certified Reference Material Series for X-ray Fluorescence Analysis of Refractories

J R R M 7 0 2 (Alumina-Zirconia-Silica Refractory)
Results of Analyses

Constituent	SiO ₂	Al ₂ O ₃	Fe ₂ O ₃	TiO ₂	CaO	MgO	Na ₂ O	K ₂ O	Cr ₂ O ₃	ZrO ₂ (+HfO ₂)	HfO ₂	ZrO ₂ ^{*3}	Unit : mass%		
													Uncertified value		
Certified value	10.0 ₁	38.2 ₁	0.37 ₄	0.21 ₁	1.55 ₆	1.98 ₂	2.02 ₇	0.58 ₀	0.11 ₁	44.7 ₁	2.09 ₀	42.6 ₂	0.00 ₄	0.02 ₈	
Laboratories	L ₁	9.96 ₀ p	38.3 ₁ e	0.36 ₇ i	0.20 ₄ i	1.56 ₇ i	1.99 ₃ i	2.04 ₅ a	0.58 ₁ a	0.12 ₀ i	44.7 ₂ m	2.06 ₁ x	—	0.00 ₄ i	0.02 ₇ e
	L ₂	9.96 ₇ p	38.0 ₄ e	0.37 ₅ c	0.21 ₀ i	1.53 ₆ i	1.94 ₉ i	2.03 ₅ f	0.58 ₇ f	0.11 ₄ i	44.7 ₅ m	2.07 ₀ i	—	0.00 ₄ i	0.03 ₀ c
	L ₃	10.1 ₆ h	38.2 ₅	0.37 ₇ c	0.19 ₆ c	1.58 ₂ a	2.00 ₂ a	1.99 ₉ a	0.56 ₄ a	0.10 ₈ a	44.8 ₂ m	2.06 ₉ x	—	—	—
	L ₄	9.92 ₉ p	38.1 ₄ v	0.37 ₁ i	0.20 ₅ i	1.56 ₂ i	1.99 ₇ i	2.04 ₃ a	0.60 ₁ a	0.11 ₁ i	44.7 ₅ m	2.12 ₁ i	—	0.00 ₄ i	—
	L ₅	9.99 ₅ h	38.2 ₉ e	0.37 ₅ c	0.19 ₈ c	1.54 ₅ a	1.98 ₉ a	2.03 ₉ a	0.54 ₉ a	0.10 ₆ a	44.6 ₂ m	2.03 ₅ x	—	0.00 ₂ a	0.02 ₇ e
	L ₆	9.99 ₂ h	38.1 ₆ e	0.36 ₉ c	0.22 ₁ c	1.55 ₉ i	1.98 ₇ i	2.01 ₃ a	0.57 ₉ a	0.10 ₄ n	44.5 ₄ m	2.11 ₈ i	—	0.00 ₄ i	0.02 ₉ e
	L ₇	10.1 ₅ p	38.3 ₈ e	0.38 ₃ c	0.23 ₁ c	1.54 ₄ a	1.98 ₃ i	2.01 ₇ a	0.59 ₁ a	0.11 ₂ a	44.7 ₉ g	2.10 ₇ i	—	—	—
	L ₈	9.94 ₆ p	38.1 ₄ v	0.379	0.22 ₀ e	1.54 ₂ a	1.95 ₉ a	2.02 ₇ a	0.58 ₅ a	0.11 ₂ a	44.7 ₀ m	2.13 ₈ x	—	0.00 ₅ a	0.02 ₆ e
Average	(\bar{X})	10.01 ₂	38.21 ₄	0.374 ₅	0.210 ₆	1.554 ₆	1.982 ₄	2.027 ₃	0.579 ₆	0.110 ₉	44.71 ₁	2.089 ₉	42.62 ₁	0.003 ₈	0.027 ₈
Standard (Reproducibility) deviation ($s_{\bar{x}}$) (Reproducibility without laboratories) $s_{I(T)}$ ^{*1}	0.09 ₀	0.10 ₁	0.005 ₆	0.012 ₂	0.016 ₁	0.018 ₃	0.016 ₃	0.016 ₁	0.005 ₀	0.09 ₄	0.036 ₀	—	0.001 ₀	0.001 ₄	
Uncertainty C (95%) ^{*2}	0.0 ₈	0.0 ₈	0.00 ₅	0.01 ₀	0.01 ₃	0.01 ₅	0.01 ₄	0.01 ₃	0.00 ₄	0.0 ₈	0.03 ₀	0.0 ₈ ^{*4}	0.00 ₁	0.00 ₂	

(Note) * 1 $s_{I(T)}$ is intermediate precision without a time condition.* 2 The half-width confidence interval C (95%) = $t_{\ell=1.05} \times s_{\bar{x}} / \sqrt{\ell}$ (ℓ = number of laboratories)* 3 $ZrO_2 = ZrO_2(+HfO_2) - HfO_2$

$$* 4 s_{\bar{x}_{ZrO_2}} = \sqrt{(s_{\bar{x}_{ZrO_2(HfO_2)}})^2 + (s_{\bar{x}_{HfO_2}})^2}$$

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J R R M 7 0 3 (Alumina-Zirconia-Silica Refractory)
Results of Analyses

Constituent	SiO ₂	Al ₂ O ₃	Fe ₂ O ₃	TiO ₂	CaO	MgO	Na ₂ O	K ₂ O	Cr ₂ O ₃	ZrO ₂ (+HfO ₂)	HfO ₂	ZrO ₂ ^{*3}	Unit : mass%		
													Uncertified value		
Certified value	14.6 ₆	46.3 ₉	0.05 ₉	0.07 ₂	0.03 ₇	0.01 ₁	0.53 ₅	0.00 ₂	0.00 ₆	38.1 ₂	0.72 ₈	37.3 ₉	0.00 ₀	0.03 ₅	
Laboratories	L ₁	14.5 ₁ p	46.6 ₃ e	0.05 ₈ i	0.07 ₀ i	0.03 ₆ i	0.01 ₂ i	0.52 ₂ a	0.00 ₄ a	0.01 ₀ i	38.2 ₂ m	0.71 ₉ x	—	0.00 ₀ i	0.03 ₇ e
	L ₂	14.6 ₆ p	46.2 ₈ e	0.06 ₀ c	0.07 ₃ c	0.03 ₆ i	0.00 ₈ i	0.53 ₂ f	0.00 ₀ f	0.00 ₄ i	37.9 ₁ m	0.70 ₃ i	—	0.00 ₀ i	0.03 ₄ e
	L ₃	14.7 ₇ h	46.3 ₄	0.06 ₄ c	0.08 ₁ e	0.03 ₈ a	0.01 ₄ a	0.53 ₈ a	0.00 ₂ a	0.02 ₂ a	38.3 ₀ m	0.70 ₉ x	—	—	—
	L ₄	14.5 ₈ p	46.2 ₂ v	0.05 ₆ i	0.06 ₄ i	0.04 ₁ i	0.01 ₁ i	0.55 ₉ a	0.00 ₀ a	0.00 ₀ i	38.2 ₀ m	0.74 ₃ i	—	0.00 ₁ i	—
	L ₅	14.5 ₈ h	46.4 ₄ e	0.06 ₀ c	0.06 ₆ c	0.03 ₅ a	0.01 ₀ a	0.54 ₆ a	0.00 ₁ a	0.00 ₂ a	38.1 ₆ m	0.71 ₃ x	—	0.00 ₀ a	0.03 ₂ e
	L ₆	14.6 ₉ h	46.2 ₅ e	0.05 ₄ c	0.07 ₂ c	0.04 ₀ i	0.01 ₁ i	0.52 ₀ a	0.00 ₆ a	0.00 ₀ n	38.0 ₃ m	0.74 ₀ i	—	0.00 ₀ i	0.04 ₀ e
	L ₇	14.8 ₈ p	46.5 ₁ e	0.05 ₅ c	0.08 ₃ c	0.03 ₄ a	0.01 ₀ i	0.53 ₀ a	0.00 ₄ a	0.00 ₄ a	38.0 ₀ g	0.74 ₂ i	—	—	—
	L ₈	14.6 ₁ p	46.4 ₄ v	0.06 ₂ c	0.06 ₇ e	0.03 ₈ a	0.01 ₄ a	0.53 ₅ a	0.00 ₂ a	0.00 ₄ a	38.1 ₀ m	0.75 ₃ x	—	0.00 ₀ a	0.03 ₀ e
Average	(\bar{X})	14.66 ₀	46.38 ₉	0.058 ₆	0.072 ₀	0.037 ₃	0.011 ₃	0.535 ₃	0.002 ₄	0.005 ₈	38.11 ₅	0.727 ₈	37.38 ₇	0.000 ₂	0.034 ₆
Standard (Reproducibility) s_x deviation (Reproducibility without laboratories) $s_{I(T)}^{*1}$	0.12 ₁	0.14 ₃	0.003 ₄	0.006 ₇	0.002 ₅	0.002 ₀	0.012 ₂	0.002 ₁	0.008 ₁	0.13 ₁	0.018 ₈	—	0.000 ₉	0.004 ₁	
Uncertainty C (95%) ^{*2}	0.1 ₀	0.1 ₂	0.00 ₃	0.00 ₆	0.00 ₂	0.00 ₂	0.01 ₀	0.00 ₂	0.00 ₇	0.1 ₁	0.01 ₆	0.1 ₁ ^{*4}	0.00 ₁	0.00 ₅	

(Note) * 1 $s_{I(T)}$ is intermediate precision without a time condition.* 2 The half-width confidence interval C (95%) = $t_{\alpha=0.05} \times s_x / \sqrt{\ell}$ (ℓ = number of laboratories)* 3 $ZrO_2 = ZrO_2(+HfO_2) - HfO_2$ * 4 $s_{x_{ZrO_2}} = \sqrt{(s_{x_{ZrO_2(HfO_2)}})^2 + (s_{x_{HfO_2}})^2}$

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J R R M 7 0 4 (Alumina-Zirconia-Silica Refractory)
Results of Analyses

Constituent	SiO ₂	Al ₂ O ₃	Fe ₂ O ₃	TiO ₂	CaO	MgO	Na ₂ O	K ₂ O	Cr ₂ O ₃	ZrO ₂ (+HfO ₂)	HfO ₂	ZrO ₂ ^{*3}	Unit : mass%		
													Uncertified value		
Certified value	42.64	19.59	0.554	1.026	0.156	0.515	0.228	0.402	0.518	34.16	0.685	33.48	0.089	0.130	
Laboratories	L ₁	42.42 p	19.71 e	0.550 i	1.032 i	0.148 i	0.494 i	0.222 a	0.400 a	0.503 i	34.29 m	0.670 x	—	0.092 i	0.138 e
	L ₂	42.74 p	19.50 e	0.552 c	1.011 i	0.149 i	0.513 i	0.234 f	0.402 f	0.511 i	34.09 m	0.689 i	—	0.094 i	0.114 c
	L ₃	42.72 h	19.57	0.553 c	1.030 c	0.164 a	0.516 a	0.229 a	0.392 a	0.511 a	34.32 m	0.659 x	—	—	—
	L ₄	42.48 p	19.57 e	0.541 i	1.033 i	0.162 i	0.535 i	0.244 a	0.404 a	0.508 i	34.17 m	0.693 i	—	0.099 i	—
	L ₅	42.73 h	19.50 e	0.559 c	1.031 c	0.152 a	0.512 a	0.210 a	0.402 a	0.541 a	34.16 m	0.697 x	—	0.058 a	0.112 e
	L ₆	42.69 h	19.53 e	0.560 c	1.034 i	0.158 i	0.510 i	0.226 a	0.402 a	0.518 i	34.12 m	0.688 i	—	0.094 i	0.172 e
	L ₇	42.70 p	19.72 e	0.565 c	1.017 x	0.152 a	0.512 i	0.236 a	0.410 a	0.532 a	34.10 g	0.693 i	—	—	—
	L ₈	42.65 p	19.65 v	0.550 c	1.020 e	0.154 a	0.528 a	0.224 a	0.400 a	0.518 a	34.06 m	0.690 x	—	0.096 a	0.116 e
Average	(\bar{X})	42.641	19.594	0.5538	1.0260	0.1549	0.5150	0.2281	0.4020	0.5178	34.164	0.6849	33.479	0.0888	0.1304
Standard (Reproducibility) deviation ($s_{\bar{x}}$)	0.118	0.091	0.0076	0.0086	0.0061	0.0118	0.0102	0.0049	0.0126	0.098	0.0140	—	0.0152	0.0259	
(Reproducibility without laboratories) $s_{I(T)}$ ^{*1}	0.086	0.102	0.0064	0.0071	0.0040	0.0043	0.0054	0.0056	0.0083	0.107	0.0067	—	0.0018	0.0032	
Uncertainty C (95%) ^{*2}	0.10	0.07	0.006	0.007	0.005	0.010	0.008	0.0040	0.010	0.08	0.011	0.08 ^{*4}	0.012	0.021	

(Note) * 1 $s_{I(T)}$ is intermediate precision without a time condition.* 3 $ZrO_2 = ZrO_2(+HfO_2) - HfO_2$ * 2 The half-width confidence interval C (95%) = $t_{\alpha=0.05} \times s_{\bar{x}} / \sqrt{\ell}$ (ℓ = number of laboratories)* 4 $s_{\bar{x}_{ZrO_2}} = \sqrt{(s_{\bar{x}_{ZrO_2(HfO_2)}})^2 + (s_{\bar{x}_{HfO_2}})^2}$

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													Uncertified value		
Certified value	2.00 ₂	64.2 ₄	0.14 ₁	2.02 ₄	0.19 ₁	0.46 ₁	0.30 ₁	0.01 ₈	2.02 ₂	28.5 ₀	0.48 ₅	28.0 ₁	0.00 ₄	0.01 ₇	
Laboratories	L ₁	2.00 ₄ c	64.2 ₅ e	0.13 ₁ i	2.04 ₉ i	0.19 ₄ i	0.45 ₅ i	0.28 ₀ a	0.01 ₉ a	2.02 ₆ i	28.3 ₅ m	0.47 ₉ x	—	0.00 ₄ i	0.04 ₀ e
	L ₂	1.97 ₄ c	64.1 ₃ e	0.14 ₀ c	2.02 ₉ i	0.18 ₀ i	0.46 ₉ i	0.30 ₀ f	0.01 ₈ f	2.01 ₉ i	28.5 ₄ m	0.48 ₇ i	—	0.00 ₅ i	0.01 ₁ e
	L ₃	2.01 ₁ h	64.0 ₅	0.14 ₄ c	2.03 ₅ c	0.20 ₈ a	0.46 ₁ a	0.32 ₆ a	0.02 ₃ a	1.99 ₆ a	28.6 ₆ m	0.47 ₂ x	—	—	—
	L ₄	1.93 ₇ p	64.1 ₅ e	0.14 ₃ i	2.04 ₈ i	0.19 ₈ i	0.48 ₃ i	0.30 ₃ a	0.01 ₉ a	2.03 ₄ i	28.7 ₃ m	0.50 ₄ i	—	0.00 ₆ i	—
	L ₅	2.08 ₅ c	64.3 ₂ e	0.13 ₉ c	1.97 ₀ c	0.18 ₂ a	0.45 ₇ a	0.28 ₉ a	0.01 ₈ a	2.02 ₉ a	28.4 ₀ m	0.47 ₁ x	—	0.00 ₀ a	0.01 ₁ e
	L ₆	2.06 ₆ c	64.4 ₂ e	0.13 ₁ c	2.04 ₈ i	0.19 ₈ i	0.46 ₇ i	0.29 ₉ a	0.01 ₄ a	2.01 ₆ i	28.4 ₁ m	0.48 ₃ i	—	0.00 ₄ i	0.01 ₂ e
	L ₇	2.01 ₀ c	64.4 ₉ e	0.15 ₀ c	1.99 ₄ x	0.18 ₄ a	0.45 ₄ a	0.31 ₃ a	0.01 ₈ a	2.03 ₇ a	28.5 ₁ m	0.48 ₇ i	—	—	—
	L ₈	1.93 ₁ c	64.1 ₂ v	0.15 ₂ c	2.02 ₀ c	0.18 ₆ a	0.44 ₁ a	0.29 ₆ a	0.01 ₈ a	2.02 ₁ a	28.3 ₇ m	0.49 ₅ x	—	0.00 ₆ a	0.01 ₂ c
Average	(\bar{X})	2.002 ₃	64.24 ₁	0.141 ₃	2.024 ₁	0.191 ₃	0.460 ₉	0.300 ₈	0.018 ₄	2.022 ₃	28.49 ₆	0.484 ₈	28.01 ₁	0.004 ₂	0.017 ₂
Standard (Reproducibility) deviation ($s_{\bar{x}}$) (Reproducibility without laboratories) $s_{I(T)}^{*1}$	0.054 ₆	0.13 ₇	0.007 ₈	0.028 ₈	0.009 ₇	0.012 ₃	0.014 ₀	0.002 ₄	0.012 ₆	0.14 ₄	0.011 ₂	—	0.002 ₀	0.012 ₅	
Uncertainty C (95%) ^{*2}	0.04 ₆	0.1 ₁	0.00 ₇	0.02 ₄	0.00 ₈	0.01 ₀	0.01 ₂	0.00 ₂	0.01 ₁	0.1 ₂	0.00 ₉	0.1 ₂ ^{*4}	0.00 ₂	0.01 ₆	

(Note) * 1 $s_{I(T)}$ is intermediate precision without a time condition.* 2 The half-width confidence interval C (95%) = $t_{\ell=1.05} \times s_{\bar{x}} / \sqrt{\ell}$ (ℓ = number of laboratories)* 3 $ZrO_2 = ZrO_2(+HfO_2) - HfO_2$ * 4 $s_{\bar{x}_{ZrO_2}} = \sqrt{(s_{\bar{x}_{ZrO_2(HfO_2)}})^2 + (s_{\bar{x}_{HfO_2}})^2}$

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(3) Analytical values : Each value is the average of two values obtained by two measurements on different days. These analysis values are shown converted into LOI (Loss on ignition) component free values from the February 22, 2008 v20080222 version on.

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(5) Date of preparation : June, 1996

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The Technical Association of Refractories, Japan

Certified Reference Material Series for X-ray Fluorescence Analysis of Refractories

J R R M 7 0 6 (Alumina-Zirconia-Silica Refractory)
Results of Analyses

Constituent	SiO ₂	Al ₂ O ₃	Fe ₂ O ₃	TiO ₂	CaO	MgO	Na ₂ O	K ₂ O	Cr ₂ O ₃	ZrO ₂ (+HfO ₂)	HfO ₂	ZrO ₂ ^{*3}	Unit : mass%		
													Uncertified value		
Certified value	39.6 ₂	26.1 ₄	0.13 ₁	3.80 ₈	1.59 ₉	0.15 ₉	3.52 ₁	0.95 ₉	0.01 ₀	24.0 ₉	1.19 ₉	22.8 ₉	0.00 ₄	0.01 ₆	
Laboratories	L ₁	39.6 ₃ p	26.1 ₅ e	0.13 ₁ i	3.77 ₆ i	1.61 ₆ i	0.16 ₅ i	3.51 ₆ a	0.97 ₁ a	0.01 ₀ i	24.1 ₂ m	1.19 ₇ x	—	0.00 ₆ i	0.01 ₇ e
	L ₂	39.6 ₃ p	26.0 ₉ e	0.13 ₅ c	3.81 ₉ x	1.59 ₂ i	0.15 ₈ i	3.56 ₈ f	0.96 ₉ f	0.01 ₁ i	24.0 ₄ m	1.13 ₄ i	—	0.00 ₄ i	0.01 ₆ e
	L ₃	39.6 ₅ p	26.1 ₆ e	0.12 ₉ c	3.78 ₉ i	1.61 ₇ i	0.16 ₁ i	3.49 ₈ a	0.97 ₂ a	0.00 ₈ i	24.0 ₇ m	1.19 ₁ i	—	0.00 ₆ i	0.01 ₄ c
	L ₄	39.5 ₉ h	26.2 ₅	0.13 ₀ e	3.82 ₂ x	1.58 ₈ a	0.14 ₆ a	3.51 ₄ a	0.96 ₃ a	0.00 ₈ a	24.0 ₀ m	1.18 ₃ x	—	—	—
	L ₅	39.5 ₇ p	26.1 ₀ e	0.13 ₁ i	3.81 ₉ i	1.59 ₀ i	0.15 ₉ i	3.54 ₅ a	0.95 ₇ a	0.01 ₂ i	24.0 ₂ m	1.20 ₈ i	—	0.00 ₅ i	—
	L ₆	39.6 ₁ h	26.0 ₆ e	0.13 ₀ e	3.78 ₉ x	1.59 ₅ a	0.16 ₁ a	3.49 ₉ a	0.95 ₁ a	0.01 ₀ a	24.0 ₈ m	1.23 ₃ x	—	0.00 ₂ a	0.01 ₇ e
	L ₇	39.6 ₃ h	26.2 ₀ e	0.12 ₉ c	3.82 ₆ c	1.61 ₁ i	0.16 ₆ i	3.50 ₅ a	0.94 ₃ a	0.00 ₈ n	24.1 ₂ m	1.21 ₂ i	—	0.00 ₁ i	0.01 ₈ e
	L ₈	39.6 ₁ p	26.1 ₃ e	0.13 ₃ c	3.80 ₉ x	1.58 ₂ a	0.15 ₈ a	3.52 ₆ a	0.94 ₃ a	0.00 ₉ a	24.2 ₄ m	1.23 ₅ x	—	0.00 ₃ a	0.01 ₁ c
Average	(\bar{X})	39.61 ₅	26.14 ₃	0.131 ₀	3.806 ₁	1.598 ₉	0.159 ₃	3.521 ₄	0.958 ₆	0.009 ₅	24.08 ₆	1.199 ₁	22.88 ₇	0.003 ₉	0.015 ₅
Standard (Reproducibility) s_x	0.03 ₀	0.06 ₄	0.002 ₀	0.019 ₂	0.013 ₀	0.006 ₂	0.024 ₃	0.011 ₇	0.001 ₅	0.07 ₉	0.032 ₁	—	0.002 ₀	0.002 ₅	
deviation ($s_{I(T)}$) * ¹	0.08 ₄	0.07 ₃	0.001 ₇	0.010 ₉	0.008 ₂	0.004 ₀	0.016 ₈	0.004 ₄	0.001 ₅	0.06 ₅	0.012 ₈	—	0.000 ₅	0.001 ₆	
Uncertainty C (95%) * ²	0.0 ₃	0.0 ₅	0.00 ₂	0.01 ₆	0.01 ₁	0.00 ₅	0.02 ₀	0.01 ₀	0.00 ₁	0.0 ₇	0.02 ₇	0.0 ₇ ^{*4}	0.00 ₂	0.00 ₃	

(Note) * 1 $s_{I(T)}$ is intermediate precision without a time condition.* 2 The half-width confidence interval C (95%) = $t_{\alpha=0.05} \times s_x / \sqrt{\ell}$ (ℓ = number of laboratories)* 3 $ZrO_2 = ZrO_2(+HfO_2) - HfO_2$ * 4 $s_{x_{ZrO_2}} = \sqrt{(s_{x_{ZrO_2(HfO_2)}})^2 + (s_{x_{HfO_2}})^2}$

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Certified Reference Material Series for X-ray Fluorescence Analysis of Refractories

J R R M 7 0 7 (Alumina-Zirconia-Silica Refractory)
Results of Analyses

Constituent	SiO ₂	Al ₂ O ₃	Fe ₂ O ₃	TiO ₂	CaO	MgO	Na ₂ O	K ₂ O	Cr ₂ O ₃	ZrO ₂ (+HfO ₂)	HfO ₂	ZrO ₂ ^{*3}	Unit : mass%		
													Uncertified value		
Certified value	21.1 ₇	55.7 ₈	1.81 ₅	0.28 ₉	1.08 ₆	0.84 ₄	0.19 ₉	0.15 ₅	0.18 ₀	18.5 ₃	0.36 ₇	18.1 ₆	0.00 ₃	0.05 ₅	
Laboratories	L ₁	21.1 ₆ p	55.6 ₉ e	1.83 ₂ i	0.28 ₅ i	1.09 ₄ i	0.84 ₈ i	0.20 ₂ a	0.15 ₄ a	0.18 ₃ i	18.5 ₂ m	0.36 ₃ x	—	0.00 ₅ i	0.05 ₂ e
	L ₂	21.2 ₀ p	55.7 ₀ e	1.81 ₂ c	0.28 ₅ i	1.08 ₃ i	0.84 ₅ i	0.19 ₃ f	0.15 ₉ f	0.17 ₆ i	18.4 ₄ m	0.37 ₈ i	—	0.00 ₄ i	0.05 ₅ c
	L ₃	21.0 ₄ p	55.8 ₃ e	1.80 ₈ c	0.29 ₂ i	1.09 ₂ i	0.84 ₁ i	0.20 ₄ a	0.15 ₀ a	0.17 ₉ i	18.4 ₅ m	0.37 ₂ i	—	0.00 ₄ i	0.05 ₈ c
	L ₄	21.2 ₅ h	55.7 ₉	1.80 ₇ c	0.29 ₀ c	1.08 ₂ a	0.84 ₈ a	0.20 ₈ a	0.15 ₄ a	0.17 ₈ a	18.7 ₃ m	0.34 ₉ x	—	—	—
	L ₅	21.1 ₉ p	55.7 ₅ e	1.82 ₀ i	0.29 ₀ i	1.07 ₈ i	0.84 ₆ i	0.20 ₆ a	0.15 ₆ a	0.17 ₄ i	18.4 ₇ m	0.37 ₃ i	—	0.00 ₄ i	—
	L ₆	21.2 ₇ h	55.8 ₅ e	1.82 ₀ c	0.29 ₁ c	1.08 ₄ a	0.84 ₄ a	0.20 ₃ a	0.15 ₂ a	0.18 ₂ a	18.4 ₆ m	0.35 ₄ x	—	0.00 ₂ a	0.05 ₆ e
	L ₇	21.0 ₂ h	55.8 ₉ e	1.82 ₆ c	0.29 ₄ c	1.09 ₂ i	0.84 ₁ i	0.17 ₇ a	0.15 ₃ a	0.18 ₂ i	18.4 ₈ m	0.37 ₆ i	—	0.00 ₁ i	0.05 ₆ c
	L ₈	21.2 ₂ p	55.7 ₇ e	1.79 ₄ c	0.282	1.08 ₀ a	0.84 ₂ a	0.20 ₀ a	0.16 ₀ a	0.18 ₄ a	18.6 ₆ m	0.37 ₄ x	—	0.00 ₂ a	0.05 ₃ c
Average	(\bar{X})	21.16 ₉	55.78 ₄	1.814 ₉	0.288 ₆	1.085 ₆	0.844 ₄	0.199 ₁	0.154 ₈	0.179 ₈	18.52 ₆	0.367 ₄	18.15 ₉	0.003 ₁	0.055 ₀
Standard (Reproducibility) deviation (s_x) (Reproducibility without laboratories) $s_{I(T)}^{*1}$	0.09 ₃	0.07 ₄	0.012 ₂	0.004 ₂	0.006 ₄	0.002 ₉	0.009 ₉	0.003 ₃	0.003 ₅	0.10 ₈	0.011 ₀	—	0.001 ₆	0.002 ₃	
Uncertainty C (95%) ^{*2}	0.0 ₈	0.0 ₆	0.01 ₀	0.00 ₄	0.00 ₅	0.00 ₂	0.00 ₈	0.00 ₃	0.00 ₃	0.0 ₉	0.00 ₉	0.0 ₉ ^{*4}	0.00 ₂	0.00 ₂	

(Note) * 1 $s_{I(T)}$ is intermediate precision without a time condition.* 2 The half-width confidence interval C (95%) = $t_{\alpha=0.05} \times s_x / \sqrt{\ell}$ (ℓ = number of laboratories)* 3 $ZrO_2 = ZrO_2(+HfO_2) - HfO_2$

$$* 4 s_{ZrO_2} = \sqrt{(s_{ZrO_2(HfO_2)})^2 + (s_{HfO_2})^2}$$

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Results of Analyses

Constituent	SiO ₂	Al ₂ O ₃	Fe ₂ O ₃	TiO ₂	CaO	MgO	Na ₂ O	K ₂ O	Cr ₂ O ₃	ZrO ₂ (+HfO ₂)	HfO ₂	ZrO ₂ ^{*3}	Unit : mass%		
													Uncertified value		
Certified value	0.54 ₇	79.6 ₃	0.80 ₁	1.02 ₁	1.17 ₄	1.64 ₉	0.08 ₉	0.74 ₆	0.29 ₈	13.8 ₉	1.03 ₄	12.8 ₆	0.00 ₁	0.00 ₂	
Laboratories	L ₁	0.54 ₇ c	79.5 ₀ e	0.80 ₅ i	1.00 ₁ i	1.18 ₂ i	1.66 ₄ i	0.07 ₄ a	0.72 ₃ a	0.29 ₈ i	13.9 ₁ m	1.01 ₉ x	—	0.00 ₂ i	0.00 ₂ e
	L ₂	0.56 ₃ c	79.7 ₂ e	0.80 ₆ c	1.03 ₅ x	1.18 ₈ i	1.66 ₄ i	0.09 ₄ f	0.75 ₄ f	0.29 ₄ i	13.9 ₆ m	1.06 ₅ i	—	0.00 ₁ i	0.00 ₂ e
	L ₃	0.54 ₃ c	79.6 ₇ e	0.80 ₁ c	1.01 ₄ i	1.18 ₅ i	1.65 ₄ i	0.08 ₇ a	0.75 ₅ a	0.29 ₉ i	13.9 ₁ m	1.03 ₂ i	—	0.00 ₁ i	0.00 ₃ c
	L ₄	0.55 ₇	79.7 ₄	0.80 ₁ e	1.03 ₈ x	1.16 ₂ a	1.64 ₄ a	0.09 ₂ a	0.75 ₁ a	0.29 ₈ a	13.8 ₀ m	1.01 ₆ x	—	—	—
	L ₅	0.55 ₉ c	79.4 ₈ e	0.79 ₁ i	1.00 ₉ i	1.15 ₄ i	1.64 ₇ i	0.09 ₆ a	0.77 ₉ a	0.29 ₇ i	13.8 ₂ m	1.03 ₉ i	—	0.00 ₁ i	—
	L ₆	0.54 ₇ c	79.6 ₇ e	0.79 ₇ e	1.02 ₅ x	1.18 ₃ a	1.64 ₂ a	0.09 ₁ a	0.74 ₃ a	0.29 ₉ a	13.8 ₇ m	1.01 ₉ x	—	0.00 ₀ a	0.00 ₂ e
	L ₇	0.52 ₃ c	79.6 ₁ e	0.80 ₇ c	1.03 ₁ i	1.18 ₆ i	1.64 ₀ i	0.08 ₅ a	0.74 ₃ a	0.29 ₅ i	13.9 ₆ m	1.01 ₆ i	—	0.00 ₀ i	0.00 ₂ e
	L ₈	0.53 ₆ c	79.6 ₇ e	0.80 ₁ c	1.01 ₅ x	1.15 ₁ a	1.63 ₄ a	0.09 ₀ a	0.72 ₄ a	0.30 ₀ a	13.8 ₉ m	1.06 ₈ x	—	0.00 ₀ a	0.00 ₀ c
Average	(\bar{X})	0.546 ₉	79.63 ₃	0.801 ₁	1.021 ₀	1.173 ₉	1.648 ₆	0.088 ₆	0.746 ₅	0.297 ₅	13.89 ₀	1.034 ₃	12.85 ₆	0.000 ₇	0.001 ₈
Standard (Reproducibility) deviation (s_x) (Reproducibility without laboratories) $s_{I(T)}$ ^{*1}	0.013 ₀	0.10 ₅	0.005 ₃	0.013 ₂	0.015 ₄	0.010 ₉	0.006 ₇	0.018 ₀	0.002 ₁	0.05 ₉	0.021 ₅	—	0.000 ₇	0.000 ₈	
Uncertainty C (95%) ^{*2}	0.01 ₁	0.0 ₉	0.00 ₄	0.01 ₁	0.01 ₃	0.00 ₉	0.00 ₆	0.01 ₅	0.00 ₂	0.0 ₈	0.01 ₈	0.0 ₅ ^{*4}	0.00 ₁	0.00 ₁	

(Note) * 1 $s_{I(T)}$ is intermediate precision without a time condition.* 2 The half-width confidence interval C (95%) = $t_{\alpha=0.05} \times s_x / \sqrt{\ell}$ (ℓ = number of laboratories)* 3 $ZrO_2 = ZrO_2(+HfO_2) - HfO_2$ * 4 $s_{\bar{x}_{ZrO_2}} = \sqrt{(s_{\bar{x}_{ZrO_2(HfO_2)}})^2 + (s_{\bar{x}_{HfO_2}})^2}$

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Certified Reference Material Series for X-ray Fluorescence Analysis of Refractories

J R R M 7 0 9 (Alumina-Zirconia-Silica Refractory)
Results of Analyses

Constituent	SiO ₂	Al ₂ O ₃	Fe ₂ O ₃	TiO ₂	CaO	MgO	Na ₂ O	K ₂ O	Cr ₂ O ₃	ZrO ₂ (+HfO ₂)	HfO ₂	ZrO ₂ ^{*3}	Unit : mass%		
													Uncertified value		
Certified value	34.4 ₅	50.4 ₅	0.47 ₇	0.09 ₁	0.52 ₅	1.21 ₀	1.04 ₀	0.21 ₈	2.92 ₂	8.52 ₃	0.18 ₄	8.34 ₀	0.00 ₂	0.00 ₉	
Laboratories	L ₁	34.5 ₆ p	50.2 ₇ e	0.47 ₂ i	0.08 ₈ i	0.52 ₆ i	1.21 ₁ i	1.01 ₆ a	0.21 ₄ a	2.93 ₃ i	8.61 ₅ m	0.17 ₆ x	—	0.00 ₄ i	0.01 ₀ e
	L ₂	34.4 ₂ p	50.4 ₃ e	0.48 ₂ c	0.08 ₈ i	0.53 ₄ i	1.20 ₉ i	1.05 ₈ f	0.21 ₈ f	2.88 ₆ i	8.50 ₈ m	0.20 ₀ i	—	0.00 ₂ i	0.01 ₀ e
	L ₃	34.4 ₈ p	50.4 ₈ e	0.47 ₄ c	0.09 ₂ i	0.52 ₄ i	1.21 ₃ i	1.04 ₀ a	0.22 ₁ a	2.93 ₉ i	8.57 ₈ m	0.19 ₀ i	—	0.00 ₄ i	0.00 ₈ c
	L ₄	34.5 ₅ h	50.5 ₀	0.47 ₃ c	0.09 ₂ c	0.51 ₉ a	1.21 ₀ a	1.03 ₆ a	0.22 ₄ a	2.94 ₃ a	8.52 ₅ m	0.15 ₈ x	—	—	—
	L ₅	34.3 ₆ p	50.4 ₃ e	0.47 ₉ i	0.09 ₇ i	0.51 ₇ i	1.20 ₉ i	1.03 ₄ a	0.21 ₄ a	2.93 ₉ i	8.51 ₂ m	0.19 ₀ i	—	0.00 ₄ i	—
	L ₆	34.4 ₁ h	50.4 ₈ e	0.47 ₉ c	0.09 ₂ c	0.52 ₆ a	1.20 ₃ a	1.04 ₈ a	0.21 ₈ a	2.92 ₈ a	8.52 ₅ m	0.17 ₉ x	—	0.00 ₁ a	0.01 ₀ e
	L ₇	34.3 ₉ h	50.5 ₄ e	0.47 ₇ c	0.09 ₁ c	0.51 ₅ i	1.21 ₁ i	1.03 ₄ a	0.21 ₂ a	2.91 ₄ i	8.36 ₅ i	0.19 ₃ i	—	0.00 ₀ i	0.01 ₀ e
	L ₈	34.4 ₅ p	50.4 ₇ e	0.47 ₉ c	0.08 ₈ e	0.53 ₉ a	1.21 ₈ a	1.05 ₄ a	0.20 ₉ a	2.89 ₆ a	8.55 ₈ m	0.18 ₂ x	—	0.00 ₂ a	0.00 ₄ c
Average	(\bar{x})	34.45 ₃	50.45 ₀	0.476 ₉	0.091 ₀	0.525 ₁	1.210 ₅	1.040 ₀	0.216 ₃	2.922 ₃	8.523 ₃	0.183 ₅	8.339 ₈	0.002 ₄	0.008 ₇
Standard (Reproducibility) s_x^-	0.07 ₀	0.08 ₃	0.003 ₆	0.003 ₁	0.008 ₅	0.004 ₀	0.013 ₅	0.004 ₈	0.021 ₀	0.072 ₀	0.012 ₈	—	0.001 ₁	0.002 ₅	
deviation (Reproducibility without laboratories) $s_{I(T)}^-$ ^{*1}	0.05 ₀	0.11 ₉	0.003 ₀	0.001 ₈	0.003 ₈	0.010 ₀	0.012 ₄	0.006 ₉	0.019 ₇	0.076 ₇	0.003 ₅	—	0.001 ₆	0.001 ₈	
Uncertainty C (95%) ^{*2}	0.0 ₆	0.0 ₇	0.00 ₃	0.00 ₃	0.00 ₇	0.00 ₃	0.01 ₁	0.00 ₄	0.01 ₈	0.06 ₀	0.01 ₁	0.06 ₁ ^{*4}	0.00 ₁	0.00 ₃	

(Note) * 1 $s_{I(T)}$ is intermediate precision without a time condition.* 2 The half-width confidence interval C (95%) = $t_{\ell=1,0.05} \times s_x^- / \sqrt{\ell}$ (ℓ = number of laboratories)* 3 $ZrO_2 = ZrO_2(+HfO_2) - HfO_2$

$$* 4 s_{x ZrO_2}^- = \sqrt{(s_{x ZrO_2(HfO_2)}^-)^2 + (s_{x HfO_2}^-)^2}$$

(1) List of laboratories : Krosaki Corporation, Kawasaki Refractories Co.,Ltd., Yotai Refractories Co.,Ltd., Asahi Glass Co.,Ltd., Harima Ceramic Co.,Ltd., Shinagawa Refractories Co.,Ltd., Toshiba Ceramics Co.,Ltd., Toshiba Monofrax Co.,Ltd.

(2) Analytical techniques : JIS R 2013(Method for chemical analysis of refractory containing alumina, zirconia and silica) a:AAS, c:colorimetry,e:Ionexchange-chelatometry, f:flammetry, g:Cupfreron Gravimetry, h:dehydratmetry+colorimetry, i:ICP-AES, m:Mandelic acid Gravimetry, p:coagulatmetry +colorimetry,v:Cupfreron Separation-chelatometry, x:XRF

(3) Analytical values : Each value is the average of two values obtained by two measurements on different days. These analysis values are shown converted into LOI (Loss on ignition) component free values from the February 22, 2008 v20080222 version on.

(4) Outlier tests were carried out by Grubbs test. The samples rejected by Grubbs tests were discussed in view of analytical techniques and it was determined whether the outliers should be adopted or not.

(5) Date of preparation : June, 1996

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J R R M 7 1 0 (Alumina-Zirconia-Silica Refractory)
Results of Analyses

Constituent	SiO ₂	Al ₂ O ₃	Fe ₂ O ₃	TiO ₂	CaO	MgO	Na ₂ O	K ₂ O	Cr ₂ O ₃	ZrO ₂ (+HfO ₂)	HfO ₂	ZrO ₂ ^{*3}	Unit : mass%		
													Uncertified value		
Certified value	5.62 ₉	82.3 ₆	1.15 ₁	3.00 ₅	0.22 ₅	0.04 ₉	1.42 ₁	0.63 ₇	1.02 ₈	4.47 ₉	1.51 ₂	2.96 ₇	0.00 ₂	0.04 ₂	
Laboratories	L ₁	5.49 ₇ p	82.1 ₉ e	1.16 ₁ i	3.02 ₁ i	0.22 ₈ i	0.05 ₀ i	1.39 ₆ a	0.64 ₂ a	1.04 ₁ i	4.59 ₂ m	1.51 ₁ x	—	0.00 ₃ i	0.04 ₁ e
	L ₂	5.59 ₈ p	82.3 ₂ e	1.19 ₇ c	2.99 ₁ x	0.22 ₄ i	0.05 ₀ i	1.46 ₉ f	0.64 ₂ f	1.05 ₉ i	4.58 ₅ m	1.52 ₄ x	—	0.00 ₂ i	0.04 ₂ c
	L ₃	5.65 ₇ c	82.4 ₉ e	1.14 ₉ c	3.01 ₈ i	0.22 ₆ i	0.05 ₀ i	1.42 ₁ a	0.63 ₉ a	1.02 ₃ i	4.50 ₅ m	1.50 ₀ i	—	0.00 ₃ i	0.04 ₄ c
	L ₄	5.68 ₈ h	82.4 ₆	1.09 ₁ e	3.02 ₃ x	0.22 ₄ a	0.04 ₆ a	1.42 ₇ a	0.63 ₂ a	1.01 ₅ a	4.46 ₀ m	1.49 ₃ x	—	—	—
	L ₅	5.59 ₆ c	82.3 ₈ e	1.11 ₉ i	2.96 ₀ i	0.22 ₀ i	0.04 ₉ i	1.42 ₀ a	0.64 ₆ a	1.00 ₃ i	4.27 ₉ m	1.51 ₄ i	—	0.00 ₃ i	—
	L ₆	5.79 ₅ c	82.3 ₄ e	1.15 ₉ c	3.00 ₂ x	0.23 ₀ a	0.04 ₉ a	1.41 ₅ a	0.63 ₇ a	1.02 ₃ a	4.40 ₁ m	1.50 ₉ x	—	0.00 ₂ a	0.04 ₀ e
	L ₇	5.76 ₀ c	82.3 ₂ e	1.15 ₉ c	3.01 ₀ c	0.22 ₄ i	0.05 ₀ i	1.40 ₃ a	0.62 ₆ a	1.01 ₇ i	4.46 ₄ i	1.47 ₉ i	—	0.00 ₀ i	0.04 ₄ c
	L ₈	5.44 ₁ c	82.4 ₁ e	1.17 ₁ c	3.01 ₁ x	0.22 ₄ a	0.05 ₁ a	1.41 ₃ a	0.63 ₁ a	1.04 ₄ a	4.54 ₈ m	1.56 ₅ x	—	0.00 ₁ a	0.04 ₄ c
Average	(\bar{X})	5.629 ₀	82.364	1.150 ₈	3.004 ₅	0.225 ₀	0.049 ₄	1.420 ₅	0.636 ₉	1.028 ₁	4.479 ₃	1.511 ₉	2.967 ₄	0.002 ₀	0.042 ₅
Standard (Reproducibility) deviation (s_x) (Reproducibility without laboratories) $s_{I(T)}^{*1}$	0.121 ₇	0.08 ₃	0.032 ₇	0.021 ₃	0.003 ₀	0.001 ₄	0.022 ₂	0.006 ₉	0.018 ₀	0.105 ₁	0.025 ₄	—	0.001 ₀	0.001 ₄	
Uncertainty C (95%) ^{*2}	0.10 ₂	0.0 ₇	0.02 ₇	0.01 ₈	0.00 ₃	0.00 ₁	0.01 ₉	0.00 ₆	0.01 ₅	0.08 ₈	0.02 ₁	0.09 ₀ ^{*4}	0.00 ₁	0.00 ₂	

(Note) * 1 $s_{I(T)}$ is intermediate precision without a time condition.* 2 The half-width confidence interval C (95%) = $t_{\alpha=0.05} \times s_x / \sqrt{\ell}$ (ℓ = number of laboratories)* 3 $ZrO_2 = ZrO_2(+HfO_2) - HfO_2$ * 4 $s_{x_{ZrO_2}} = \sqrt{(s_{x_{ZrO_2(HfO_2)}})^2 + (s_{x_{HfO_2}})^2}$

(1) List of laboratories : Krosaki Corporation, Kawasaki Refractories Co.,Ltd., Yotai Refractories Co.,Ltd., Asahi Glass Co.,Ltd., Harima Ceramic Co.,Ltd., Shinagawa Refractories Co.,Ltd., Toshiba Ceramics Co.,Ltd., Toshiba Monofrax Co.,Ltd.

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